

**Notice of References Cited**

Application/Control No.

10/582,202

Applicant(s)/Patent Under  
Reexamination  
FUJITA ET AL.

Examiner

KRISTY A. HAUPT

Art Unit

2876

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,039,250 A	03-2000	Ito et al.	235/380
*	B	US-6,032,857 A	03-2000	Kitagawa et al.	235/379
*	C	US-2001/0014869 A1	08-2001	Yoshizawa, Katsumi	705/14
*	D	US-7,360,091 B2	04-2008	Aikawa et al.	713/172
*	E	US-2003/0018577 A1	01-2003	Fukushima et al.	705/39
*	F	US-2003/0033203 A1	02-2003	Inoue et al.	705/14
*	G	US-2003/0163376 A1	08-2003	Inoue et al.	705/14
*	H	US-2004/0049421 A1	03-2004	Hagiwara, Kotaro	705/014
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.